

An X-ray diffractometer using mirage diffraction. Erratum

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Errors in the article by Fukamachi, Jongsuksawat, Ju, Negishi, Hirano & Kawamura [*J. Appl. Cryst.* (2014), **47**, 1267–1272] are corrected.

In the article by Fukamachi *et al.* (2014), there are errors in Fig. 2 (§2, p. 1268) and in equations (12)–(16) (§4, p. 1270–1271).

The equations should read

$$\delta WX_0 = \frac{|\delta \mathbf{K}_E|}{\cos \theta_B}, \quad (12)$$

$$\frac{\delta E}{E} = \frac{|\chi_h|}{2} \delta W, \quad (13)$$

$$\delta E = E \delta \alpha \frac{\sin 2\theta_B}{2}, \quad (14)$$

$$\delta E = \frac{|\chi_h|E}{2} \left[1 - \left(1 + \frac{\beta^2 x^2}{4} \right)^{1/2} \right] \quad (15)$$

and

$$dE = \frac{|\chi_h|}{2} \left(1 + \frac{\beta^2 x^2}{4} \right)^{-1/2} \frac{\beta^2}{4} E x dx. \quad (16)$$

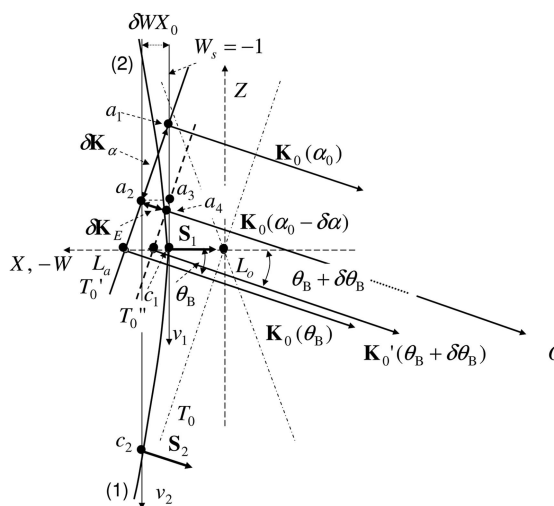


Figure 1

As the last sentence of the caption of Fig. 2 of Fukamachi *et al.* (2014), the following sentence should be added: $|\delta \mathbf{K}_E|$ is the distance between a_2 and a_4 .

Then, rather than the value of 11 meV for $|\delta E|$ in the first line of the left column on p. 1271, the value should read 10 meV. Rather than -3.0 , -5.0 , -6.7 and -7.9 meV for the values of δE in Table 1, they should read -2.7 , -4.6 , -6.2 and -7.3 meV, respectively. In spite of these corrections, the conclusions are not affected.

As the last sentence of the caption of Fig. 2 of Fukamachi *et al.* (2014), the following sentence should be added: $|\delta \mathbf{K}_E|$ is the distance between a_2 and a_4 . Fig. 2 of Fukamachi *et al.* (2014) is updated as Fig. 1 in the current article to reflect the correction.

References

Fukamachi, T., Jongsuksawat, S., Ju, D., Negishi, R., Hirano, K. & Kawamura, T. (2014). *J. Appl. Cryst.* **47**, 1267–1272.